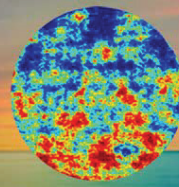
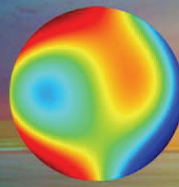


S-Series | 1MP



Fizeau Interferometer for Surface and Wavefront Metrology 1-Megapixel Imaging and Three Optional Sources

| System Overview | S50 1MP | S100 1MP | S150 1MP |
|--|---|--------------------|-----------------------|
| Output Diameter | 51 mm (2 inch) | 102 mm (4 inch) | 153 mm (6 inch) |
| Optical Centerline | 108 mm (4.25) | 108 mm (4.25 inch) | 133 mm (5.24 mm) |
| Focus Range (position readout) | ±0.5 meters | ±2.0 meters | ±4.5 meters |
| Interferometer Size (L x W x H) | 63 x 29 x 18 cm | 70 x 32 x 26 cm | 90.2 x 40.8 x 23.9 cm |
| Weight | 25 kg (55 lbs) | 33 kg (73 lbs) | 50 kg (110 lbs) |
| Measurement Techniques | Fast/Sensitive Spectral Synchronous, Vibration-Tolerant PSI Plus Vibration-Insensitive Carrier Fringe | | |
| Alignment System | 2-Spot with reticle with 2° Capture Range | | |
| Light Source | SCI SpectrÄ 2.0, HeNe Laser, and ÄTLas Wavelength Shifting | | |
| Laser Frequency Stability | <0.0001 nm | | |
| Temporal Coherence Length | SCI SpectrÄ 2.0 ≤2 meters, HeNe Laser >100 meters, ÄTLas ≤3 meters | | |
| Output Polarization | Circular (Linear optional for birefringent part measurement) | | |
| Camera Resolution | 1022 x 1022 | | |
| Camera Frame Rate (max) | 90 Hz (25 Hz with SCI source) | | |
| Shutter Speed (shortest) | 9 μs | | |
| Camera Digitization | 8 bit | | |
| Computer & Software | High-Performance PC, Windows11, 64-bit OS & REVEAL Software | | |
| Mounting Configurations | Horizontal or Vertical | | |
| Performance | | | |
| Image Resolution | 100μm (10 l/mm) | 200 μm (5 l/mm) | 300μm (3.3l/mm) |
| Image Distortion | <0.1% | | |
| Fringe Resolution | >300 fr/aperture | | |
| Retrace Error ³ @ 256 fringes | < λ/15 | | |
| RMS Simple Repeatability ¹ | <0.6 nm RMS 2σ | | |
| RMS Wavefront Repeatability ² | <0.6 nm RMS 2σ | | |
| Measurable Part Reflectivity | 0.1% to 40% direct and >41% with attenuation filter or coatings | | |
| Environment | | | |
| Temperature | 15°C to 30C | | |
| ΔT/Δt | <1.0°C/15 min | | |
| Humidity | 5 to 95% relative, non-condensing | | |
| Vibration Isolation | Isolation System recommended for VTPSI | | |

¹ RMS Simple Repeatability Test: The RMS for 36 sequential measurements with each measurement the average of 16 measurements each of a short <2 mm plano cavity
² RMS Wavefront Repeatability Test: Measure 36 sequential Measurements (M1, M2, ... M30) each consisting of 16 averages. Then average all 36 measurements create a synthetic reference, "Ref". RMS wavefront repeatability equals the 2X the standard deviation of all 30 Ref - Mn results.
³ Retrace Error is defined as the PV residual error between a nulled measurement (the reference), subtracted from a measurement with 500 fringes of tilt, and expressed by the first 36 Zernike polynomials
⁴ λ/20 optionally available
⁵ Resolution is detector limited at 800 lines/aperture

REVEAL

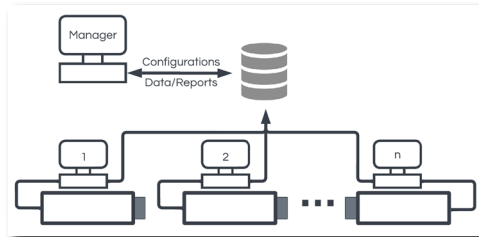
Metrology Software for Interferometers

Introducing REVEAL 23

REVEAL 23 Starts with the REVEAL Launcher

UNIQUE and NEW!: No interferometer is an island...with REVEAL 23

Load measurement recipes and report forms from a central controlled library. Automatically save data to your database. Eliminates setup errors, and user-to-user variations by standardizing the entire measurement process from a central, password controlled location.

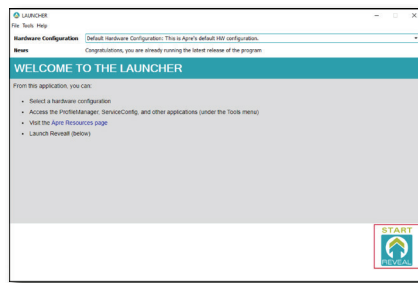


NEW! Setup user access and passwords:

In the Profile Manager grant or restrict global or individual access to measurements. Assign what can be edited, where data is saved, and then password (encrypted) protect.

NEW! Configure your hardware with a click:

ÄPRE state-of-the-art interferometers use multiple sources, which means multiple hardware configurations. Just switch the source, click the hardware configuration and launch REVEAL 23 to start measuring.



Inside REVEAL 23

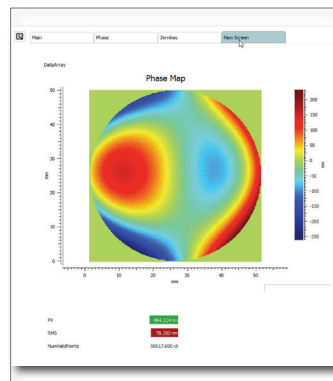
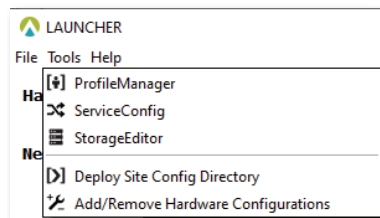
REVEAL functionality is maintained: All the menus, results, screens, data and setups are maintained. So there is no learning curve.

More Analyses are Standard: Standard analysis, Optical Shop Testing and Fourier Analysis are included in the standard package so licensing is easier.

NEW! Create Your Own Custom Screens: With an easy to use editor, display the graphs and results required and even set GO/NOGO tolerance flags on important results. Then save your custom screen for future use. The screen at the right was configured in five minutes! It's that easy.

NEW! "Undo" mask shapes. You're in the middle of creating a mask and you want to make a change. The new Undo function takes you back one step to retry. Less time lost, and more freedom to experiment.

NEW! Event Log: Sometimes "things" happen. To correct an error and to get production up and running the Event Log gives you just the important information. Now you can act on it, or contact ÄPRE with the key information, and save time.



Over nine years ago REVEAL innovated interferometer software

- Traceable metrology via the analysis tree, saved with as-measured (.rvl) data
- Data analysis based on international standards and leading laboratories worldwide
- Apply filters/masks to data along the entire analysis tree
- Fast, consistent reporting via a default, and customizable report library
- 64-bit operation to handle modern 9-Megapixel and larger cameras without crashing
- Remote training and debugging via TeamViewer
- Clean, browser like, non-overlapping screens
- Compatible with historic .dat data files

Now REVEAL 23 tightens QC with enterprise control, increases security, and lets you customize screens



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520.639.8195
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Contact ÄPRE to get REVEAL 23 on your system today.